



GO TO PRODUCT

- Component for the Opens test, for capacitive testing of semiconductor chips for open circuits, short circuits and soldering faults
- Suitable for all Keysight 307x test systems with software version 9.2 or higher
- Improved repeating accuracy, test coverage and error detection in comparison to VTEP technology



1:1

Application

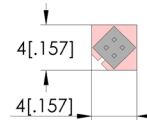
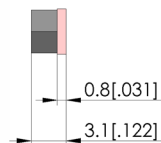
The nanoVTEP test probes are used for capacitive testing of integrated circuits in order to check the wire-bonded connections inside an integrated circuit for breakage, short circuits, and solder defects. The nanoVTEP test probes are Keysight's latest vectorless opens test solution and replace the existing VTEP test probes. In addition to significantly improved repeating accuracy, test coverage, and defect detection, the new nanoVTEP probes offer up to 40% amplification of weak signal, as the amplifier is placed close to the sensor plate. The new nanoVTEP probes only work in conjunction with the nanoVTEP MUX boards. Both nanoVTEP and VTEP probes can be combined in one test fixture.

Note:

For professional customisation of the KEYSIGHT nanoVTEP probes, refer to the customising instructions INFO 4250.

Note:

nanoVTEP probes can be safely used on all Keysight 307x test systems that have software version 9.2 or newer. If the software version you are using is older than 9.2, please contact the test system manufacturer Keysight directly



General data

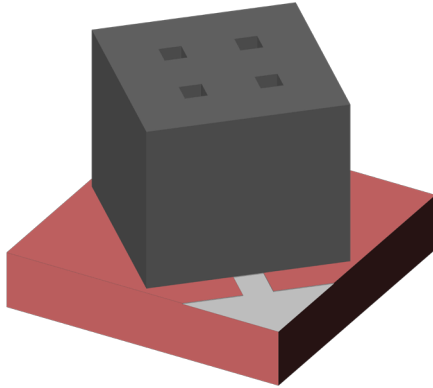
Product group:	Opens tests
Series:	OTC
Type:	Keysight Vectorless Test
Version:	nanoVTEP SP 0.16 inch
Accessory type:	Customising accessories
Scope of delivery:	Without nanoVTEP amplifier
Width:	4 mm [.157 in]
Height:	3.1 mm [.122 in]
Min. temperature:	10 °C [50 °F]
Max. temperature:	60 °C [140 °F]
RoHS-compliant:	Yes

Compatible with

Vacuum test fixtures (VA):	VA 2070S/L
Interchangeable kits (WS):	

Technical data

Length:	4 mm [.157 in]
Outer dimensionS (WxDxH):	4 x 4 x 3.1 mm [.157 x .157 x .122 in]



Accessories

Part no.	Designation	Version
114385	OTC-KS-NV-EP-ST-KS-G2	nanoVTEP (Amplifier, barrel and receptacle)
108710	OTE-KS-NV-064-MUX	nanoVTEP signal conditioner board
108711	OTE-KS-NV-064-MUX-REF	nanoVTEP signal conditioner board ConnectCheck

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